



General Description

- Trench Power MOSFET technology
- Combined of low $R_{DS(ON)}$ and wide Safe Operating Area (SOA)
- Higher in-rush current enabled for faster start-up and shorter down time
- RoHS 2.0 and Halogen-Free Compliant
- $T_j=175^{\circ}\text{C}$ Rated

Applications

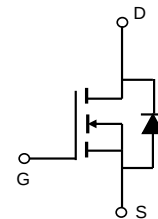
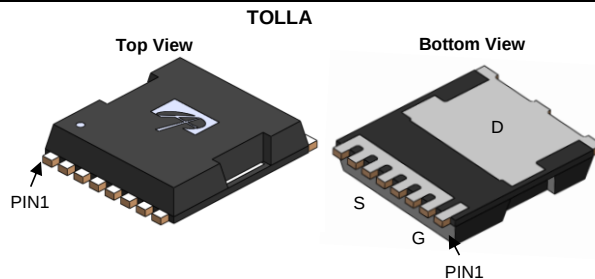
- Load switch
- BMS
- Motor

Product Summary

V_{DS}	150V
I_D (at $V_{GS}=10\text{V}$)	200A
$R_{DS(ON)}$ (at $V_{GS}=10\text{V}$)	< 3.9m Ω
$R_{DS(ON)}$ (at $V_{GS}=6\text{V}$)	< 5.5m Ω

100% UIS Tested
100% Rg Tested

Max $T_j=175^{\circ}\text{C}$



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOTL66515	TOLLA	Tape & Reel	2000

Absolute Maximum Ratings $T_A=25^{\circ}\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	150	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	200	A
	$T_C=100^{\circ}\text{C}$	140	
Pulsed Drain Current ^C	I_{DM}	730	
Continuous Drain Current	I_{DSM}	30	A
	$T_A=70^{\circ}\text{C}$	25	
Avalanche Current ^C	I_{AS}	100	A
Avalanche energy L=0.1mH ^C	E_{AS}	500	mJ
Power Dissipation ^B	P_D	428	W
	$T_C=100^{\circ}\text{C}$	214	
Power Dissipation ^A	P_{DSM}	10	W
	$T_A=70^{\circ}\text{C}$	7	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	$^{\circ}\text{C}$

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	10	15	$^{\circ}\text{C/W}$
Maximum Junction-to-Ambient ^{A, D}		35	45	$^{\circ}\text{C/W}$
Maximum Junction-to-Case	$R_{\theta JC}$	0.25	0.35	$^{\circ}\text{C/W}$

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V	150			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =150V, V _{GS} =0V T _J =55°C			1 5	μA
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2	2.5	3	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =20A T _J =125°C		3.2 6.7	3.9 8.2	mΩ
		V _{GS} =6V, I _D =20A		4.4	5.5	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =20A		45		S
V _{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.7	1	V
I _S	Maximum Body-Diode Continuous Current				200	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =75V, f=1MHz		16700		pF
C _{oss}	Output Capacitance			720		pF
C _{rss}	Reverse Transfer Capacitance			17		pF
R _g	Gate resistance	f=1MHz	1	2	3	Ω
SWITCHING PARAMETERS						
Q _{g(10V)}	Total Gate Charge	V _{GS} =10V, V _{DS} =75V, I _D =20A		190	270	nC
Q _{gs}	Gate Source Charge			55		nC
Q _{gd}	Gate Drain Charge			15		nC
Q _{oss}	Output Charge	V _{GS} =0V, V _{DS} =75V		260		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =75V, R _L =3.75Ω, R _{GEN} =3Ω		33		ns
t _r	Turn-On Rise Time			28		ns
t _{D(off)}	Turn-Off DelayTime			128		ns
t _f	Turn-Off Fall Time			35		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =20A, di/dt=500A/μs		84		ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =20A, di/dt=500A/μs		1.18		μC

- A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The Power dissipation P_{DSM} is based on R_{θJA} ≤ 10s and the maximum allowed junction temperature of 175° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.
- B. The power dissipation P_D is based on T_{J(MAX)}=175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Single pulse width limited by junction temperature T_{J(MAX)}=175° C.
- D. The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=175° C. The SOA curve provides a single pulse rating.
- G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

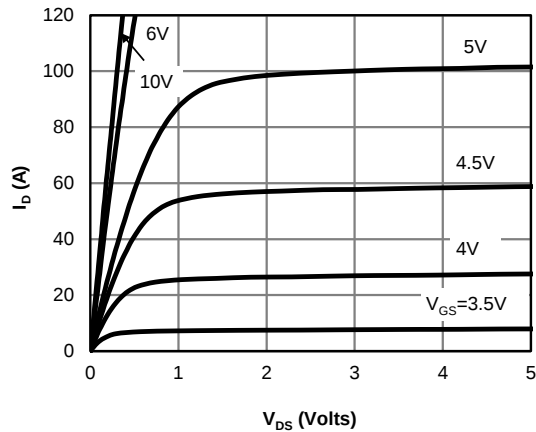


Figure 1: On-Region Characteristics (Note E)

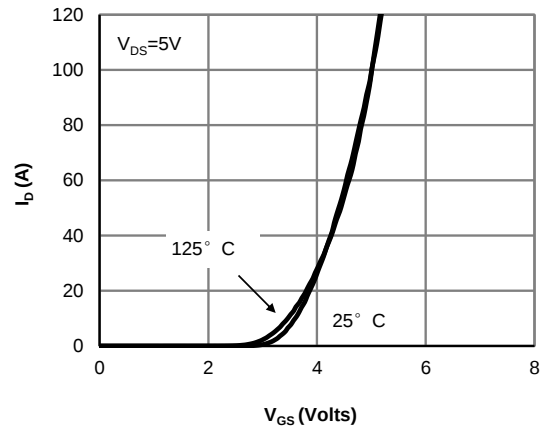


Figure 2: Transfer Characteristics (Note E)

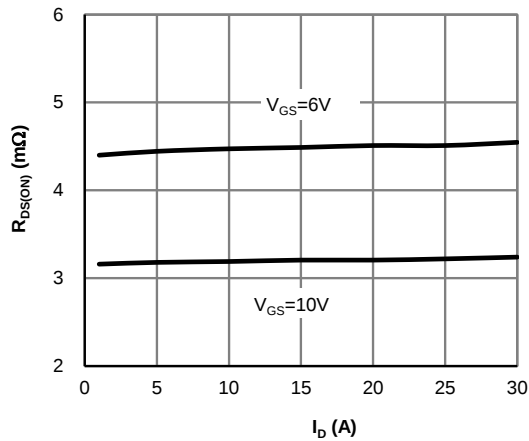


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

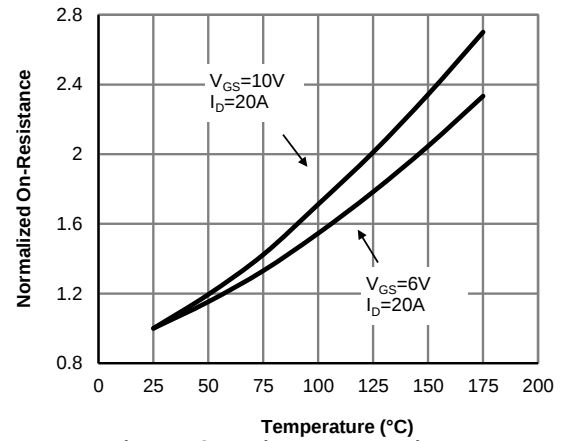


Figure 4: On-Resistance vs. Junction Temperature (Note E)

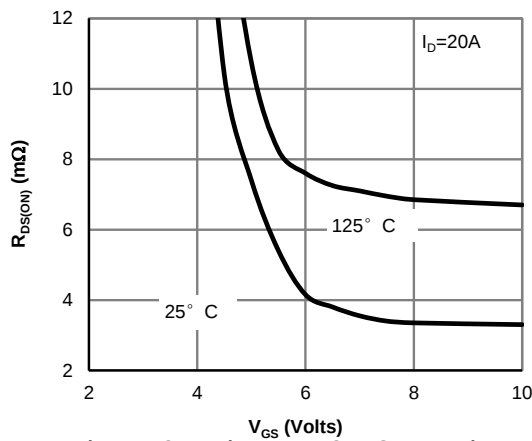


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

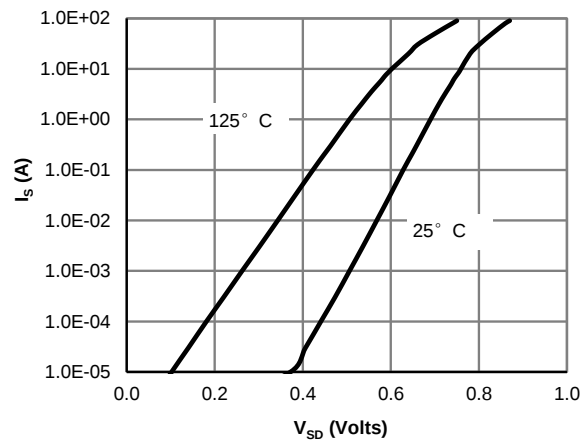
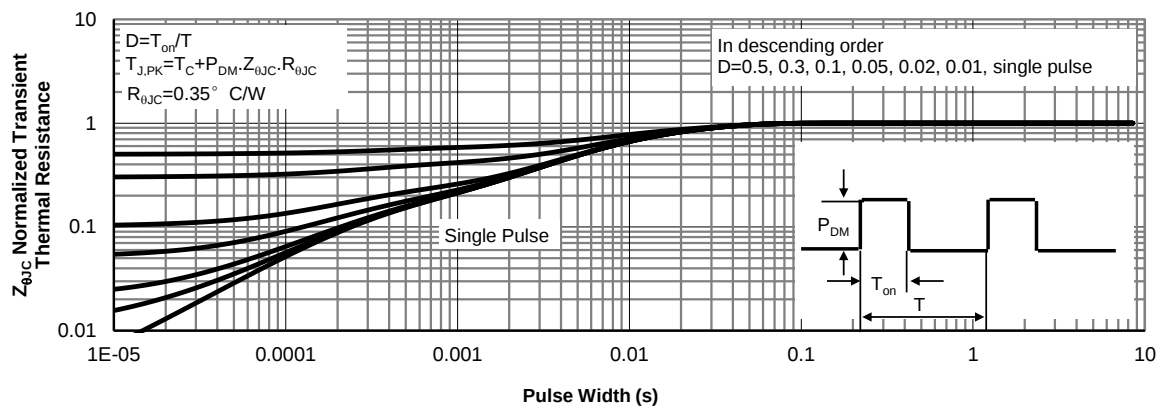
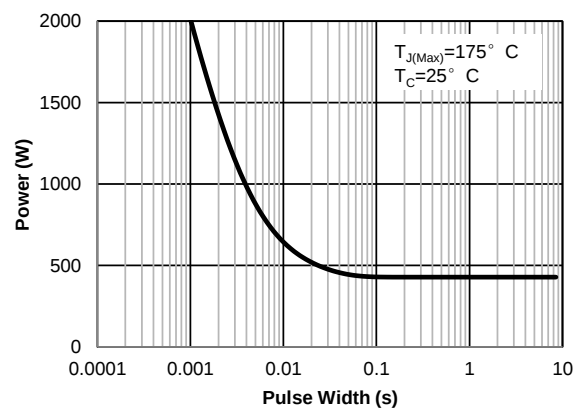
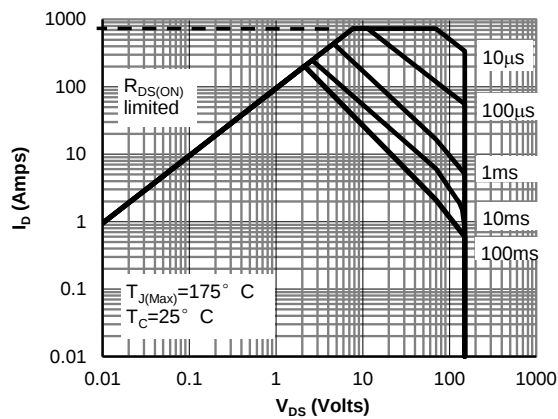
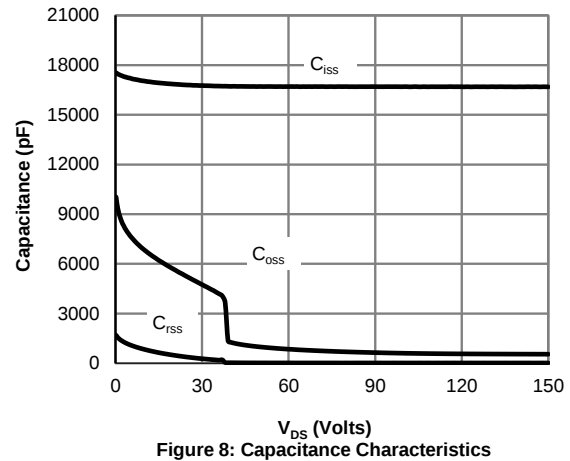
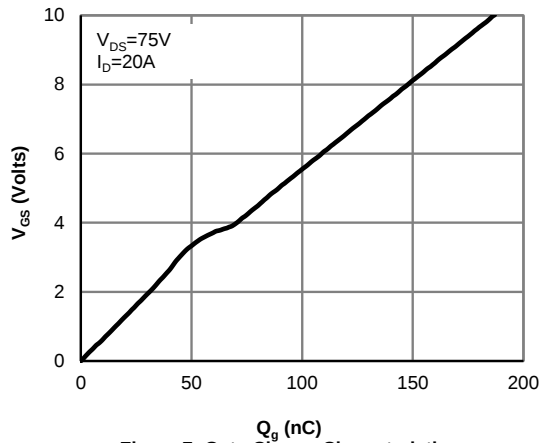


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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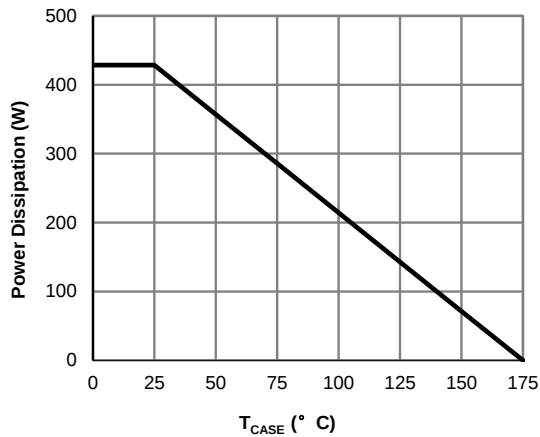


Figure 12: Power De-rating (Note F)

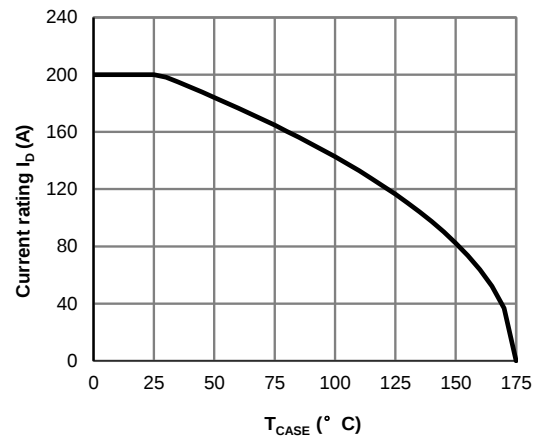


Figure 13: Current De-rating (Note F)

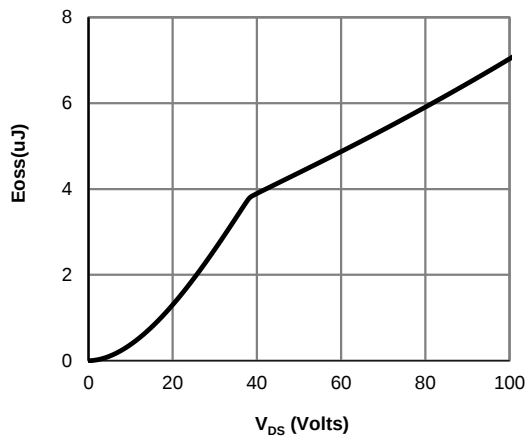


Figure 14: Coss stored Energy

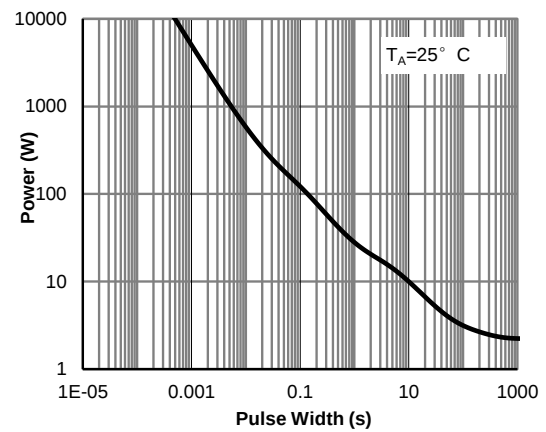


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note G)

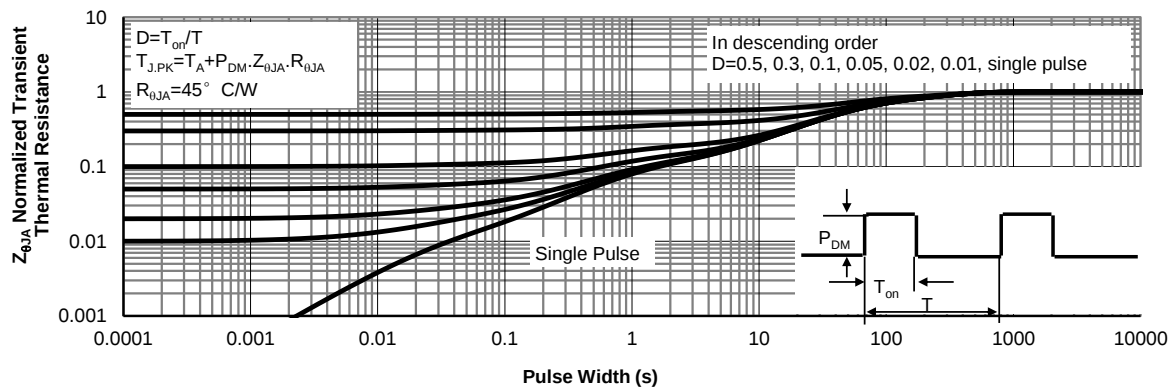


Figure 16: Normalized Maximum Transient Thermal Impedance (Note G)

Figure A: Gate Charge Test Circuit & Waveforms

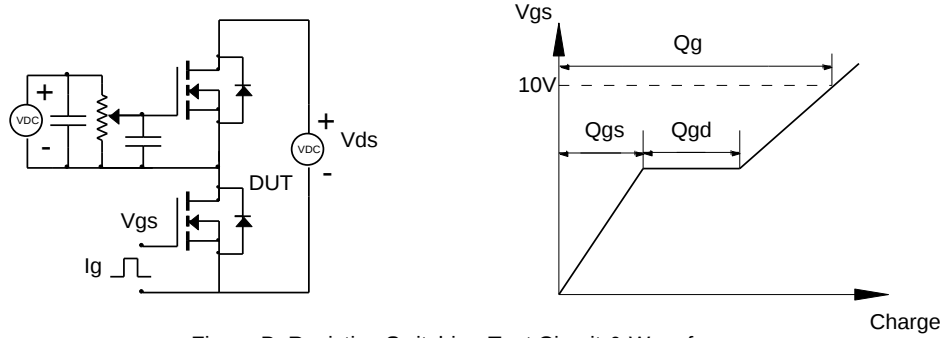


Figure B: Resistive Switching Test Circuit & Waveforms

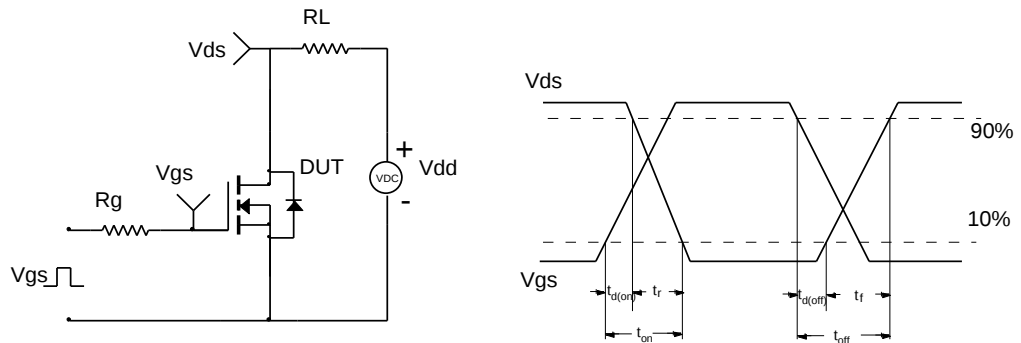


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

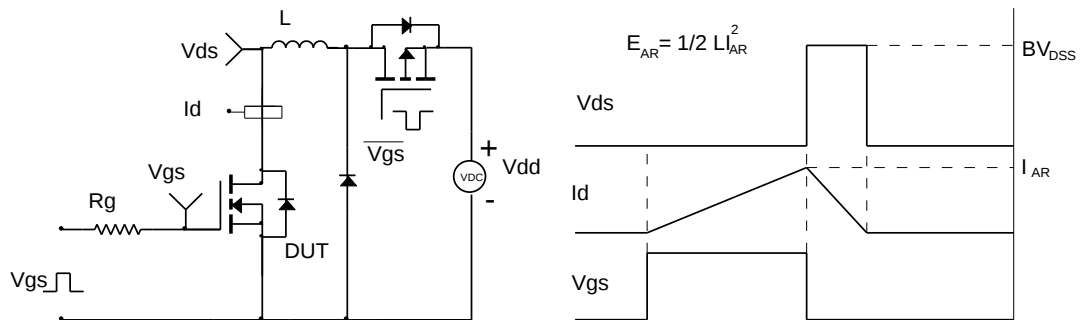


Figure D: Diode Recovery Test Circuit & Waveforms

